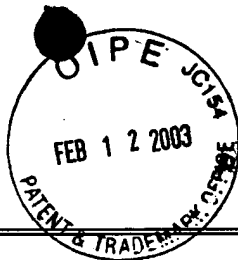


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PATENT

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(PTO-1449)

ATTY. DOCKET NO.  
87280.1762

SERIAL NO.  
10/021,048

APPLICANT  
Ohler L. Kinney, Jr., et al.

FILING DATE  
12/19/01

GROUP  
3749-1724

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U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A	CP	3,875,269	04/01/75	Forchini, et al.	261	111	01/18/73
B		4,416,836	11/22/83	Sinek	261	112	12/03/81
C		4,422,983	12/27/83	Bardo, et al.	261	24	06/16/82
D		6,250,610	06/26/01	Flaherty, et al.	261	109	08/23/99
E		5,487,849	01/30/96	Curtis	261	30	12/03/93
F	CP	5,569,415	10/29/96	Phelps	261	23.1	09/18/95
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FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
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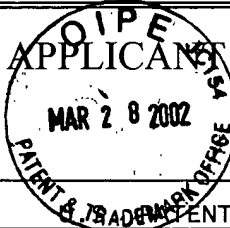
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH	CP	International Search Report dated January 14, 2003
II	CP	International Search Report dated January 14, 2003
JJ		
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

<b>LIST OF ART CITED BY APPLICANT</b> (PTO-1449)						ATTY. DOCKET NO. 87280.1762		SERIAL NO. 10/021,048	
				APPLICANT Ohler L. Kinney, Jr., et al.				FILING DATE December 19, 2001	

DOMESTIC PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A	CB	4,514,202	04/30/85	Kinney, Jr. et al.	55	440	09/12/84
B							
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	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
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EXAMINER <i>OS. BL</i>	DATE CONSIDERED <i>8-28-03</i>
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